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1c672 U.S. PRO
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IN THE U.S. PATENT AND TRADEMARK OFFICE

Applicant(s): KIM, Ha Zoong

Application No.:

Group:

Filed: June 29, 1999

Examiner:

For: TDDb TEST PATTERN AND METHOD FOR TESTING TDDb OF MOS
CAPACITOR DIELECTRIC

L E T T E R

Assistant Commissioner for Patents
Box Patent Application
Washington, D.C. 20231

June 29, 1999
0465-0582P

Sir:

Under the provisions of 35 USC 119 and 37 CFR 1.55(a), the applicant hereby claims the right of priority based on the following application(s):

<u>Country</u>	<u>Application No.</u>	<u>Filed</u>
REPUBLIC OF KOREA	35677/1998	08/31/98
REPUBLIC OF KOREA	568/1999	01/12/99

A certified copy of the above-noted application(s) is(are) attached hereto.

If necessary, the Commissioner is hereby authorized in this, concurrent, and future replies, to charge payment or credit any overpayment to deposit Account No. 02-2448 for any additional fees required under 37 C.F.R. 1.16 or under 37 C.F.R. 1.17; particularly, extension of time fees.

Respectfully submitted,

BIRCH, STEWART, KOLASCH & BIRCH, LLP

By: 

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Ha Zoong KIM
June 29, 1999
465-582P

대한민국 특허청 1 of 2

KOREAN INDUSTRIAL
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별첨 사본은 아래 출원의 원본과 동일함을 증명함.

This is to certify that the following application annexed hereto
is a true copy from the records of the Korean Industrial
Property Office.

출원번호 : 1998년 특허출원 제35677호
Application Number

출원년월일 : 1998년 8월 31일
Date of Application

출원인 : 엘지반도체주식회사
Applicant(s)



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COMMISSIONER

